

Data sheet acquired from Harris Semiconductor

# CD74AC02, CD74ACT02

**Quad 2-Input NOR Gate** 

#### September 1998

#### **Features**

- Typical Propagation Delay
  - 6ns at  $V_{CC} = 5V$ ,  $T_A = 25^{\circ}C$ ,  $C_L = 50pF$
- Exceeds 2kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latchup-Resistant CMOS Process and Circuit Design
- Speed of Bipolar FAST™/AS/S with Significantly Reduced Power Consumption
- Balanced Propagation Delays
- AC Types Feature 1.5V to 5.5V Operation and Balanced Noise Immunity at 30% of the Supply
- ±24mA Output Drive Current
  - Fanout to 15 FAST™ ICs
  - Drives  $50\Omega$  Transmission Lines

## Description

The CD74AC02 and CD74ACT02 are quad 2-input NOR gates that utilize the Harris Advanced CMOS Logic technology.

## **Ordering Information**

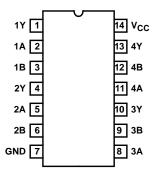
PART NUMBER	TEMP. RANGE ( <sup>O</sup> C)			
CD74AC02E	-55 to 125	14 Ld PDIP	E14.3	
CD74ACT02E	-55 to 125	14 Ld PDIP	E14.3	
CD74AC02M	-55 to 125	14 Ld SOIC	M14.15	
CD74ACT02M	-55 to 125	14 Ld SOIC	M14.15	

#### NOTES:

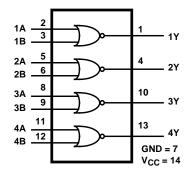
- 12. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
- 13. Wafer and die for this part number is available which meets all electrical specifications. Please contact your local sales office or Harris customer service for ordering information.

#### **Pinout**

CD74AC02, CD74ACT02 (PDIP, SOIC) TOP VIEW



# Functional Diagram



#### **TRUTH TABLE**

INP	UTS	OUTPUTS
Α	В	Y
L	L	Н
Н	L	L
L	Н	L
Н	Н	L

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## **Absolute Maximum Ratings**

DC Supply Voltage, V <sub>CC</sub> 0.5V to 6V
DC Input Diode Current, I <sub>IK</sub>
For $V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$
DC Output Diode Current, I <sub>OK</sub>
For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$
DC Output Source or Sink Current per Output Pin, IO
For $V_O > -0.5V$ or $V_O < V_{CC} + 0.5V$
DC V <sub>CC</sub> or Ground Current, I <sub>CC or</sub> I <sub>GND</sub> (Note 3) ±100mA

#### **Thermal Information**

Thermal Resistance (Typical, Note 5)	$\theta_{JA}$ (oC/W)
PDIP Package	90
SOIC Package	175
Maximum Junction Temperature (Plastic Package)	150 <sup>o</sup> C
Maximum Storage Temperature Range	65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300°C

## **Operating Conditions**

Temperature Range, T <sub>A</sub> 55°C to 125°C
Supply Voltage Range, V <sub>CC</sub> (Note 4)
AC Types
ACT Types
DC Input or Output Voltage, V <sub>I</sub> , V <sub>O</sub> 0V to V <sub>CC</sub>
Input Rise and Fall Slew Rate, dt/dv
AC Types, 1.5V to 3V 50ns (Max)
AC Types, 3.6V to 5.5V
ACT Types, 4.5V to 5.5V

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

#### NOTES:

- 14. For up to 4 outputs per device, add  $\pm 25 \text{mA}$  for each additional output.
- 15. Unless otherwise specified, all voltages are referenced to ground.
- 16.  $\theta_{JA}$  is measured with the component mounted on an evaluation PC board in free air.

## **DC Electrical Specifications**

		1	TEST CONDITIONS Vcc		V <sub>CC</sub> 25°C			C TO °C		C TO 5°C	
PARAMETER	SYMBOL	V <sub>I</sub> (V)	I <sub>O</sub> (mA)	(V)	MIN	MAX	MIN	MAX	MIN	MAX	UNITS
AC TYPES	AC TYPES										
High Level Input Voltage	V <sub>IH</sub>	-	-	1.5	1.2	-	1.2	-	1.2	-	V
				3	2.1	-	2.1	-	2.1	-	V
				5.5	3.85	-	3.85	-	3.85	-	V
Low Level Input Voltage	V <sub>IL</sub>	-	-	1.5	-	0.3	-	0.3	-	0.3	V
				3	-	0.9	-	0.9	-	0.9	V
				5.5	-	1.65	-	1.65	-	1.65	V
High Level Output Voltage	V <sub>OH</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.05	1.5	1.4	-	1.4	-	1.4	-	V
			-0.05	3	2.9	-	2.9	-	2.9	-	V
			-0.05	4.5	4.4	-	4.4	-	4.4	-	V
			-4	3	2.58	-	2.48	-	2.4	-	V
			-24	4.5	3.94	-	3.8	-	3.7	-	V
			-75 (Note 6, 7)	5.5	-	-	3.85	-	-	-	V
			-50 (Note 6, 7)	5.5	-	-	-	-	3.85	-	V

# CD74AC02, CD74ACT02

## DC Electrical Specifications (Continued)

		TEST CONDITIO		v <sub>cc</sub>	Vcc <sup>25</sup>		-40°C TO 85°C		-55°C TO 125°C		
PARAMETER	SYMBOL	V <sub>I</sub> (V)	I <sub>O</sub> (mA)	(V)	MIN	MAX	MIN	MAX	MIN	MAX	UNITS
Low Level Output Voltage	$V_{OL}$	V <sub>IH</sub> or V <sub>IL</sub>	0.05	1.5	-	0.1	-	0.1	-	0.1	V
			0.05	3	-	0.1	-	0.1	-	0.1	V
			0.05	4.5	-	0.1	-	0.1	-	0.1	V
			12	3	-	0.36	-	0.44	-	0.5	V
			24	4.5	-	0.36	-	0.44	-	0.5	V
			75 (Note 6, 7)	5.5	-	-	ı	1.65	ı	ı	<b>V</b>
			50 (Note 6, 7)	5.5	-	-	-	-	-	1.65	٧
Input Leakage Current	Н	V <sub>CC</sub> or GND	-	5.5	1	±0.1	ı	±1	ı	±1	μΑ
Quiescent Supply Current SSI	I <sub>CC</sub>	V <sub>CC</sub> or GND	0	5.5	-	4	ı	40	ı	80	μΑ
ACT TYPES											
High Level Input Voltage	V <sub>IH</sub>	-	-	4.5 to 5.5	2	-	2	-	2	-	V
Low Level Input Voltage	V <sub>IL</sub>	-	-	4.5 to 5.5	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage	V <sub>OH</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.05	4.5	4.4	-	4.4	-	4.4	-	V
			-24	4.5	3.94	-	3.8	-	3.7	-	٧
			-75 (Note 6, 7)	5.5	ı	-	3.85	-	ı	ı	٧
			-50 (Note 6, 7)	5.5	-	-	-	-	3.85	-	٧
Low Level Output Voltage	$V_{OL}$	V <sub>IH</sub> or V <sub>IL</sub>	0.05	4.5	-	0.1	-	0.1	-	0.1	٧
			24	4.5	-	0.36	-	0.44	-	0.5	V
			75 (Note 6, 7)	5.5	-	-	-	1.65	-	-	V
			50 (Note 6, 7)	5.5	-	-	-	-	-	1.65	٧
Input Leakage Current	l <sub>l</sub>	V <sub>CC</sub> or GND	-	5.5	-	±0.1	-	±1	-	±1	μΑ
Quiescent Supply Current SSI	Icc	V <sub>CC</sub> or GND	0	5.5	-	4	-	40	-	80	μΑ
Additional Supply Current per Input Pin TTL Inputs High 1 Unit Load	Δl <sub>CC</sub>	V <sub>CC</sub> -2.1	-	4.5 to 5.5	-	2.4	-	2.8	-	3	mA

#### NOTES:

## **ACT Input Load Table**

INPUT	UNIT LOAD
All	0.32

NOTE: Unit load is  $\Delta I_{CC}$  limit specified in DC Electrical Specifications Table, e.g., 2.4mA max at 25°C.

<sup>17.</sup> Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.

<sup>18.</sup> Test verifies a minimum  $50\Omega$  transmission-line-drive capability at  $85^{\circ}$ C,  $75\Omega$  at  $125^{\circ}$ C.

## CD74AC02, CD74ACT02

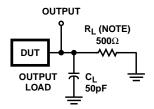
## **Switching Specifications** Input $t_r$ , $t_f = 3$ ns, $C_L = 50$ pF (Worst Case)

			-40°C TO 85°C		-55	OC TO 12	5°C		
PARAMETER	SYMBOL	V <sub>CC</sub> (V)	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
AC TYPES					•				
Propagation Delay, Input to	t <sub>PLH</sub> , t <sub>PHL</sub>	1.5	-	-	131	-	-	144	ns
Output		3.3 (Note 9)	4.1	-	14.6	4	-	16.1	ns
		5 (Note 10)	3	-	10.4	2.9	-	11.5	ns
Input Capacitance	Cl	-	-	-	10	-	-	10	pF
Power Dissipation Capacitance	C <sub>PD</sub> (Note 11)	-	-	55	-	-	55	-	pF
ACT TYPES				•	•		•	•	•
Propagation Delay, Input to Output	t <sub>PLH</sub> , t <sub>PHL</sub>	5 (Note 10)	3.1	-	11.1	3.1	-	12.2	ns
Input Capacitance	Cl	-	-	-	10	-	-	10	pF
Power Dissipation Capacitance	C <sub>PD</sub> (Note 11)	-	-	55	-	-	55	-	pF

#### NOTES:

- 19. Limits tested at 100%.
- 20. 3.3V Min at 3.6V, Max at 3V.
- 21. 5V Min at 5.5V, Max at 4.5V.

22.  $C_{PD}$  is used to determine the dynamic power consumption per gate. AC:  $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ ACT:  $P_D = V_{CC}^2 f_i (C_{PD} + C_L) + V_{CC} \Delta I_{CC}$  where  $f_i$  = input frequency,  $C_L$  = output load capacitance,  $V_{CC}$  = supply voltage.



NOTE: For AC Series Only: When  $V_{CC}$  = 1.5V,  $R_L$  = 1k $\Omega$ .

	CD74AC	CD74ACT
Input Level	V <sub>CC</sub>	3V
Input Switching Voltage, V <sub>S</sub>	0.5 V <sub>CC</sub>	1.5V
Output Switching Voltage, V <sub>S</sub>	0.5 V <sub>CC</sub>	0.5 V <sub>CC</sub>

FIGURE 2. PROPAGATION DELAY TIMES

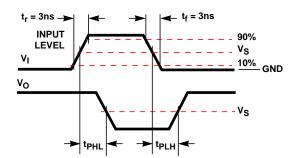


FIGURE 3. PROPAGATION DELAY TIMES

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